

IGBT - Field Stop II NGTB60N65FL2WG

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop (FS) Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss.

Features

- Extremely Efficient Trench with Field Stop Technology
- $T_{Jmax} = 175^{\circ}C$
- Soft Fast Reverse Recovery Diode
- Optimized for High Speed Switching
- 5 μs Short–Circuit Capability
- These are Pb-Free Devices

Typical Applications

- Solar Inverters
- Uninterruptible Power Supplies (UPS)
- Welding

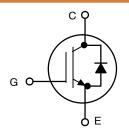
ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-emitter Voltage	V _{CES}	650	V
Collector Current @ T _C = 25°C @ T _C = 100°C	I _C	100 60	Α
Diode Forward Current @ T _C = 25°C @ T _C = 100°C	l _F	100 60	Α
Diode Pulsed Current T _{PULSE} Limited by T _J Max	I _{FM}	240	Α
Pulsed Collector Current, T _{pulse} Limited by T _{Jmax}	I _{CM}	240	Α
Short–circuit Withstand Time V_{GE} = 15 V, V_{CE} = 400 V, $T_{J} \le +150^{\circ}C$	t _{SC}	5	μs
Gate-emitter Voltage	V_{GE}	±20	V
Transient Gate-emitter Voltage (T _{PULSE} = 5 μs, D < 0.10)		±30	
Power Dissipation @ T _C = 25°C @ T _C = 100°C	P _D	595 265	W
Operating Junction Temperature Range	TJ	–55 to +175	°C
Storage Temperature Range	T _{stg}	-55 to +175	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T _{SLD}	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

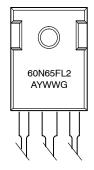
1

60 A, 650 V V_{CEsat} = 1.64 V E_{off} = 0.66 mJ





MARKING DIAGRAM



60N65FL2 = Specific Device Code
A = Assembly Location

A = Assembly Location
Y = Year
WW = Work Week
G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping
NGTB60N65FL2WG	TO-247 (Pb-Free)	30 Units / Rail

THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.28	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ heta JC}$	0.62	°C/W
Thermal resistance junction-to-ambient	$R_{ hetaJA}$	40	°C/W

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC	•			•		
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0 \text{ V, I}_{C} = 500 \mu\text{A}$	V _{(BR)CES}	650	_	-	V
Collector-emitter saturation voltage	V _{GE} = 15 V, I _C = 60 A V _{GE} = 15 V, I _C = 60 A, T _J = 175°C	V _{CEsat}	1.50 -	1.64 2.00	2.00	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_{C} = 350 \mu A$	V _{GE(th)}	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	V _{GE} = 0 V, V _{CE} = 650 V V _{GE} = 0 V, V _{CE} = 650 V, T _{J =} 175°C	I _{CES}	- -	- 5.0	0.1 -	mA
Gate leakage current, collector-emitter short-circuited	V _{GE} = 20 V , V _{CE} = 0 V	I _{GES}	-	-	200	nA
DYNAMIC CHARACTERISTIC	•			•		
Input capacitance		C _{ies}	_	7193	-	pF
Output capacitance	V _{CE} = 20 V, V _{GE} = 0 V, f = 1 MHz	C _{oes}	-	311	-	
Reverse transfer capacitance	1	C _{res}	-	202	-	
Gate charge total		Q_{g}	-	318	-	nC
Gate to emitter charge	V _{CE} = 480 V, I _C = 60 A, V _{GE} = 15 V	Q _{ge}	-	65	-	
Gate to collector charge	1	Q _{gc}	-	163	-	
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD					
Turn-on delay time		t _{d(on)}	-	117	-	ns
Rise time	1	t _r	-	53	-	
Turn-off delay time	T _J = 25°C	t _{d(off)}	-	265	-	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 60 \text{ A}$ $R_{g} = 10 \Omega$	t _f	-	75	-	
Turn-on switching loss	$V_{GE} = 0 \text{ V} / 15 \text{ V}$	E _{on}	-	1.59	-	mJ
Turn-off switching loss	1	E _{off}	-	0.66	-	
Total switching loss	1	E _{ts}	-	2.25	-	
Turn-on delay time		t _{d(on)}	-	113	-	ns
Rise time	1	t _r	-	55	-	
Turn-off delay time	T _J = 150°C	t _{d(off)}	-	277	-	
Fall time	$V_{CC} = 400 \text{ V}, I_{C} = 60 \text{ A}$	t _f	-	1.0	-	
Turn-on switching loss	$R_g = 10 \Omega$ $V_{GE} = 0 \text{ V}/15 \text{ V}$	E _{on}	-	2.0	-	mJ
Turn-off switching loss	1	E _{off}	-	1.1	-	
Total switching loss	1	E _{ts}	-	3.1	-	ĺ
DIODE CHARACTERISTIC				•		•
Forward voltage	$V_{GE} = 0 \text{ V, } I_F = 60 \text{ A}$ $V_{GE} = 0 \text{ V, } I_F = 60 \text{ A, } T_J = 175^{\circ}\text{C}$	V _F	1.50 -	2.13 2.26	2.80	V
Reverse recovery time	T _{.1} = 25°C	t _{rr}	-	96	-	ns
Reverse recovery charge	$I_F = 60 \text{ Å}, V_R = 400 \text{ V}$	Q _{rr}	_	0.39	-	μC
Reverse recovery current	di _F /dt = 200 A/μs	I _{rrm}	_	6.8	-	Α
Reverse recovery time	T _J = 175°C	t _{rr}	-	177	-	ns
Reverse recovery charge	$I_F = 60 \text{ A}, V_B = 400 \text{ V}$	Q _{rr}	-	1.53	-	μC
Reverse recovery current	di _F /dt = 200 A/μs	I _{rrm}	_	13	_	Α

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

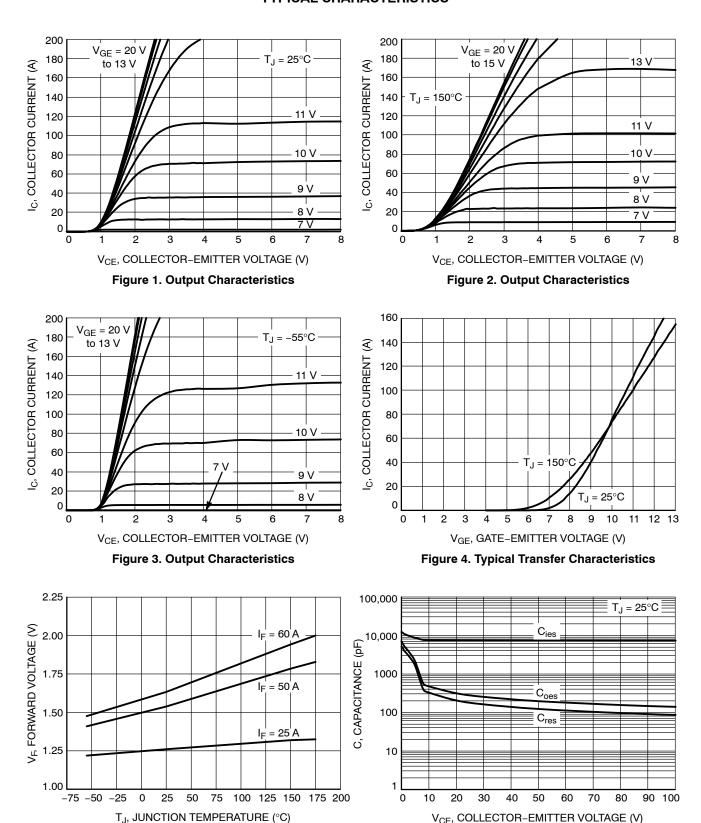


Figure 6. Typical Capacitance

Figure 5. V_F vs. T_J

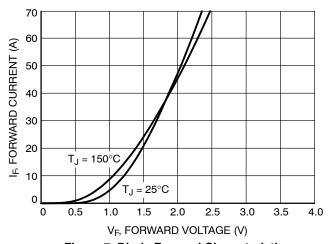


Figure 7. Diode Forward Characteristics

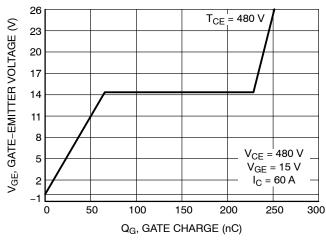


Figure 8. Typical Gate Charge

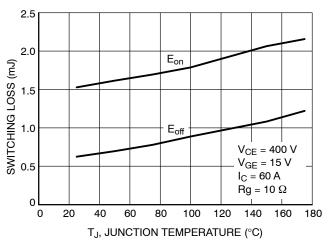


Figure 9. Switching Loss vs. Temperature

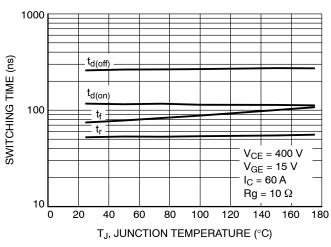


Figure 10. Switching Time vs. Temperature

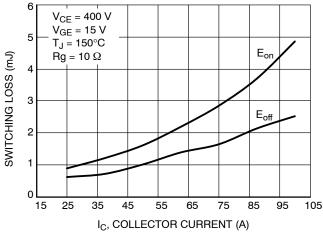


Figure 11. Switching Loss vs. I_C

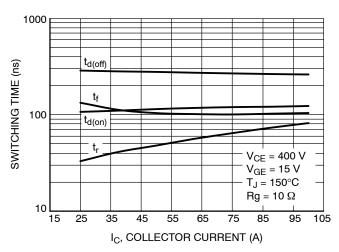


Figure 12. Switching Time vs. I_C

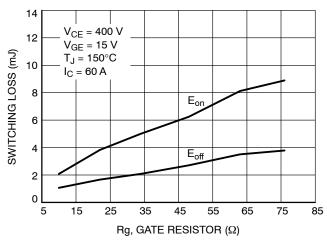


Figure 13. Switching Loss vs. Rg

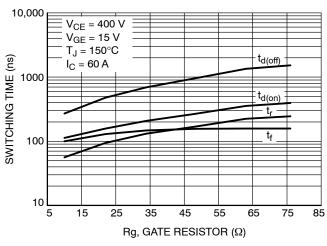


Figure 14. Switching Time vs. Rg

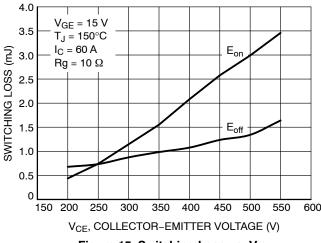


Figure 15. Switching Loss vs. V_{CE}

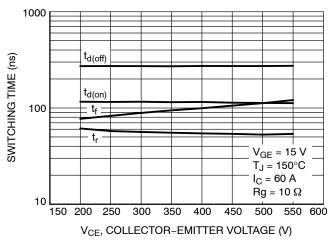


Figure 16. Switching Time vs. V_{CE}

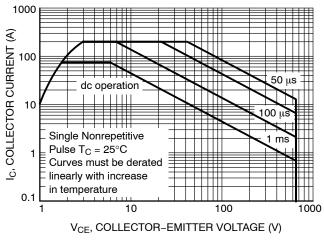


Figure 17. Safe Operating Area

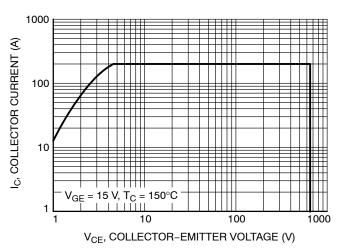


Figure 18. Reverse Bias Safe Operating Area

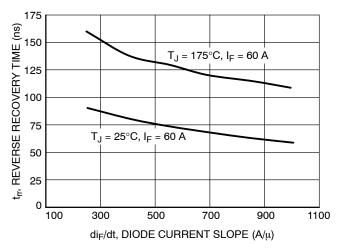


Figure 19. t_{rr} vs. di_F/dt ($V_R = 400 V$)

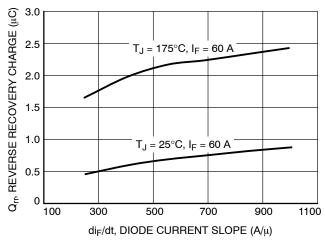


Figure 20. Q_{rr} vs. di_F/dt ($V_R = 400 V$)

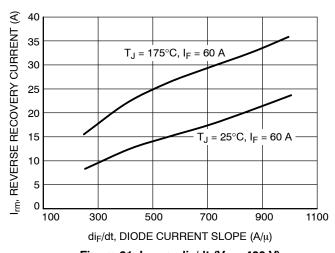


Figure 21. I_{rm} vs. di_F/dt ($V_R = 400 V$)

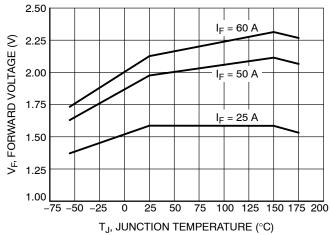


Figure 22. V_F vs. T_J

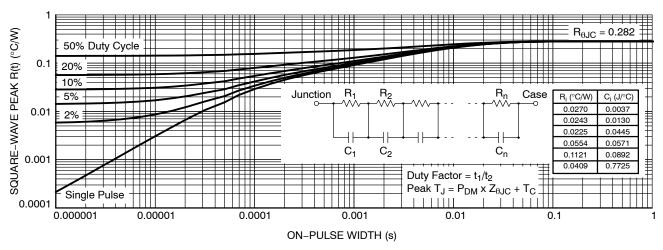


Figure 23. IGBT Transient Thermal Impedance

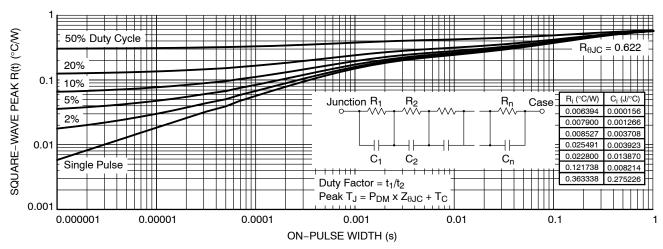
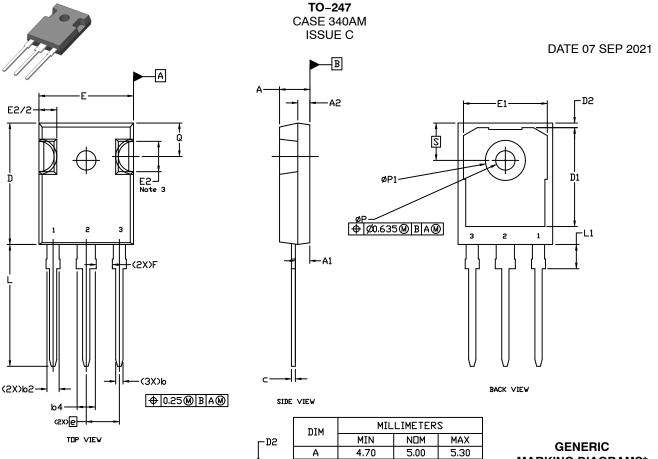
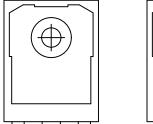
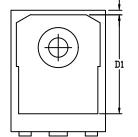


Figure 24. Diode Transient Thermal Impedance







NOTE 4 HEATSINK SHAPES

NOTES:

- 1. DIMENSIONING AND TOLERANCE AS PER ASME Y14.5M, 2009.
- 2. ALL DIMENSION ARE IN MILLIMETERS.
- SLOT REQUIRED, NOTCH MAY BE ROUNDED. 3.
- OPTIONAL BACK SIDE HEATSINK SHAPE.
- DIMENSIONS ARE EXCLUSIVE OF BURRS AND MOLD FLASH.
 DIMENSIONS D AND E ARE MEASURED AT THE OUTERMOST EXTREME OF THE PLASTIC BODY.
- 6. DIMENSIONS AT TO BE MEASURED IN THE REGION DEFINED BY L1.
- 7. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

A1	2.20	2.40	2.60
A2	1.80	2.00	2.20
b	1.07	1.20	1.33
b2	1.65	2.12	2.35
b4	2.60	3.12	3.40
C	0.45	0.60	0.75
D	20.80	21.00	21.34
D1	16.30		
D2	0.75		
Ε	15.50	16.00	16.25
E1	13.80		
E2	4.32	4.90	5.49
e	5.45 BSC		
F	2.655		
L	19.80	20.00	20.80
L1	3.81	4.20	4.35

3.65

6.20

3.60

6.00

6.15 BSC

3.55

6.60

5.40

MARKING DIAGRAMS*





XXXX = Specific Device Code = Assembly Location

Υ = Year WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	98AON77284F	Electronic versions are uncontrolled except when accessed directly from the Document Repositor Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	TO-247		PAGE 1 OF 1

P1

Q

S

ON Semiconductor and un are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMi., and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer p

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT: Email Requests to: orderlit@onsemi.com

onsemi Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative